

RADIATION TEST REPORT

PRODUCT: AD590MFQMLR

MASK:

FILE:

DATE CODE:

GAMMA: 0, 100K

GAMMA SOURCE: Co60

DOSE RATE: 48.24 rad/sec

FACILITIES: National Semiconductor
Sunnyvale, Ca.

TESTED: 12-Jun-03

The RADTESTSM DATA SERVICE is a compilation of radiation test results on Analog Devices' Space grade products. It is designed to assist customers in selecting the right product for applications where radiation is a consideration. Many products manufactured by Analog Devices, Inc. have been shown to be radiation tolerant to most tactical radiation environments, Analog Devices, Inc. does not make any claim to maintain or guarantee these levels of radiation tolerance without lot qualification test.

It is the responsibility of the Procuring Activity to screen products from Analog Devices, Inc. for compliance to Nuclear Hardness Critical Items (HCI) specifications.

WARNING:

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Ambient Error (T0) @VS= 5V, TA=25°C

T#1	C°	
SN	Initial	100K
10	-0.360	-0.360
1	-0.284	-4.267
3	-0.340	-4.230
5	-0.358	-3.982
6	-0.351	-3.004
min	-0.358	-4.267
max	-0.284	-3.004
stdev	0.034	0.592
average	-0.333	-3.871
+3S	-0.232	-2.096
-3S	-0.434	-5.645

